

7-46-07-05

KS54AHCT 74
KS74AHCT

Dual D-Type Positive-Edge-Triggered Flip-Flops with Preset and Clear

FEATURES

- Function, pin-out, speed and drive compatibility with 54/74ALS logic family
- Low power consumption characteristic of CMOS
- High-Drive-Current outputs:
 $I_{OL} = 8 \text{ mA @ } V_{OL} = 0.5V$
- Inputs and outputs interface directly with TTL, NMOS and CMOS devices
- Wide operating voltage range: 4.5V to 5.5V
- Characterized for operation over industrial and military temperature ranges:
KS74AHCT: -40°C to $+85^{\circ}\text{C}$
KS54AHCT: -55°C to $+125^{\circ}\text{C}$
- Package options include plastic "small outline" packages, standard plastic and ceramic 300-mil DIPs

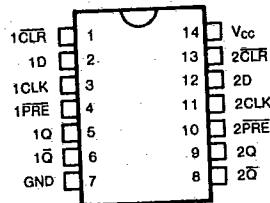
DESCRIPTION

These devices contain two independent positive-edge-triggered D-type flip-flops. Each flip-flop has its own data, clock, preset and clear inputs and complementary Q and \bar{Q} outputs. The preset and clear inputs are active-low and operate independently of the clock. Data at the D input is transferred to the Q outputs on the positive transition of the clock, provided setup requirements have been met.

These devices provide speeds and drive capability equivalent to their ALSTTL counterparts and yet maintain CMOS power levels. The input and output voltage levels allow direct interface with TTL, NMOS and CMOS devices without any external components.

All inputs and outputs are protected from damage due to static discharge by internal diode clamps to V_{CC} and ground.

PIN CONFIGURATION

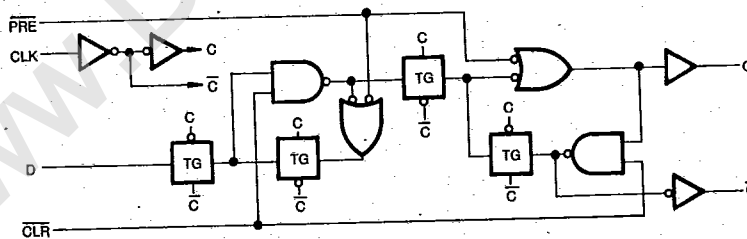


FUNCTION TABLE

Inputs				Outputs	
$\overline{\text{PRE}}$	$\overline{\text{CLR}}$	CLK	D	Q	\bar{Q}
L	H	X	X	H	L
H	L	X	X	L	H
L	L	X	X	H*	H*
H	H	↑	H	H	L
H	H	↑	L	L	H
H	H	L	X	No Change	No Change
H	H	H	X	No Change	No Change
H	H	↓	X	No Change	No Change

* Both outputs will remain high as long as $\overline{\text{PRE}}$ and $\overline{\text{CLR}}$ are low, but the output states are unpredictable if $\overline{\text{PRE}}$ and $\overline{\text{CLR}}$ go high simultaneously.

LOGIC DIAGRAM



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Absolute Maximum Ratings*

Supply Voltage Range V_{CC} -0.5V to +7V
 DC Input Diode Current, I_{IK}
 ($V_I < -0.5V$ or $V_I > V_{CC} + 0.5V$) ± 20 mA
 DC Output Diode Current, I_{OK}
 ($V_O < -0.5V$ or $V_O > V_{CC} + 0.5V$) ± 20 mA
 Continuous Output Current Per Pin, I_O
 ($-0.5V < V_O < V_{CC} + 0.5V$) ± 35 mA
 Continuous Current Through
 V_{CC} or GND pins ± 125 mA
 Storage Temperature Range, T_{stg} -65°C to +150°C
 Power Dissipation Per Package, P_d † 500 mW

* Absolute Maximum Ratings are those values beyond which permanent damage to the device may occur. These are stress ratings only and functional operation of the device at or beyond them is not implied. Long exposure to these conditions may affect device reliability.

† Power Dissipation temperature derating:
 Plastic Package (N): -12mW/°C from 65°C to 85°C
 Ceramic Package (J): -12mW/°C from 100°C to 125°C

Recommended Operating Conditions

Supply Voltage, V_{CC} 4.5V to 5.5V
 DC Input & Output Voltages*, V_{IN} , V_{OUT} 0V to V_{CC}
 Operating Temperature
 Range KS74AHCT: -40°C to +85°C
 KS54AHCT: -55°C to +125°C

Input Rise & Fall Times, t_r , t_f Max 500 ns

* Unused inputs must always be tied to an appropriate logic voltage level (either V_{CC} or GND)

DC ELECTRICAL CHARACTERISTICS ($V_{CC}=5V \pm 10\%$ Unless Otherwise Specified)

Characteristic	Symbol	Test Conditions	$T_a = 25^\circ C$		KS74AHCT $T_a = -40^\circ C$ to $+85^\circ C$		KS54AHCT $T_a = -55^\circ C$ to $+125^\circ C$		Unit
			Typ	Guaranteed Limits					
Minimum High-Level Input Voltage	V_{IH}			2.0	2.0	2.0	2.0		V
Maximum Low-Level Input Voltage	V_{IL}			0.8	0.8	0.8	0.8		V
Minimum High-Level Output Voltage	V_{OH}	$V_{IN}=V_{IH}$ or V_{IL} $I_O=-20\mu A$ $I_O=-4mA$	V_{CC} 4.2	$V_{CC}-0.1$ 3.98	$V_{CC}-0.1$ 3.84	$V_{CC}-0.1$ 3.7			V
Maximum Low-Level Output Voltage	V_{OL}	$V_{IN}=V_{IH}$ or V_{IL} $I_O=20\mu A$ $I_O=4mA$ $I_O=8mA$	0	0.1 0.26 0.39	0.1 0.33 0.5	0.1 0.4			V
Maximum Input Current	I_{IN}	$V_{IN}=V_{CC}$ or GND		± 0.1	± 1.0	± 1.0			μA
Maximum Quiescent Supply Current	I_{CC}	$V_{IN}=V_{CC}$ or GND $I_{OUT}=0\mu A$		4.0	40.0	80.0			μA
Additional Worst Case Supply Current	ΔI_{CC}	per input pin $V_I=2.4V$ other Inputs: at V_{CC} or GND $I_{OUT}=0\mu A$		2.7	2.9	3.0			mA

KS54AHCT
KS74AHCT 74Dual D-Type Positive-Edge-Triggered
Flip-Flops with Preset and ClearAC ELECTRICAL CHARACTERISTICS (Input $t_r, t_f \leq 2$ ns), AHCT74

Characteristic	Symbol	Conditions†	T _a = 25°C	KS74AHCT		KS54AHCT		Unit
			V _{CC} = 5.0V	T _a = -40°C to +85°C	T _a = -55°C to +125°C	V _{CC} = 5.0V ± 10%		
			Typ	Min	Max	Min	Max	
Maximum Clock Frequency	f _{max}	C _L = 50pF	55	34		30		MHz
Propagation Delay, CLK to Q or \bar{Q}	t _{PLH}		10		17		20	ns
	t _{PHL}		10		17		20	ns
Propagation Delay, PRE or CLR to Q or \bar{Q}	t _{PLH}		9		15		18	ns
	t _{PHL}	9		15		18	ns	
Setup Time before CLK†	Data	t _{su}	7	12		15		ns
	PRE or CLR Inactive		5	8		10		ns
Hold Time, Data after CLK†	t _h		-3	0		0		ns
Pulse Width	CLK High or Low	t _w	9	15		17		ns
	PRE or CLR Low		9	15		17		ns
Input Capacitance	C _{IN}		5					pF
Power Dissipation Capacitance*	C _{PD}							pF

* C_{PD} determines the no-load dynamic power dissipation: P_D = C_{PD} V_{CC}² f + I_{CC} V_{CC}.

† For AC switching test circuits and timing waveforms see section 2.

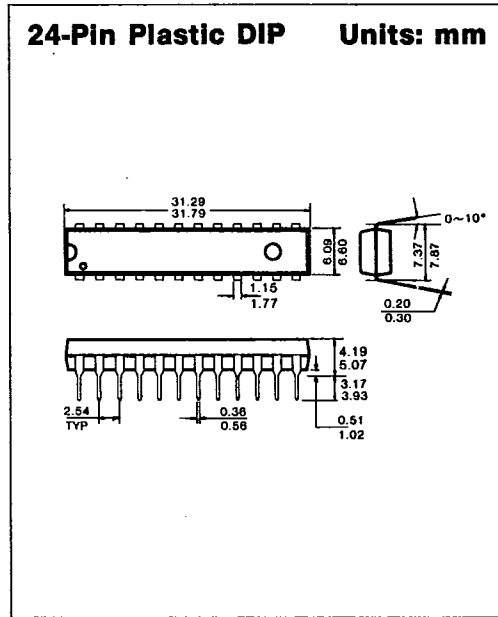
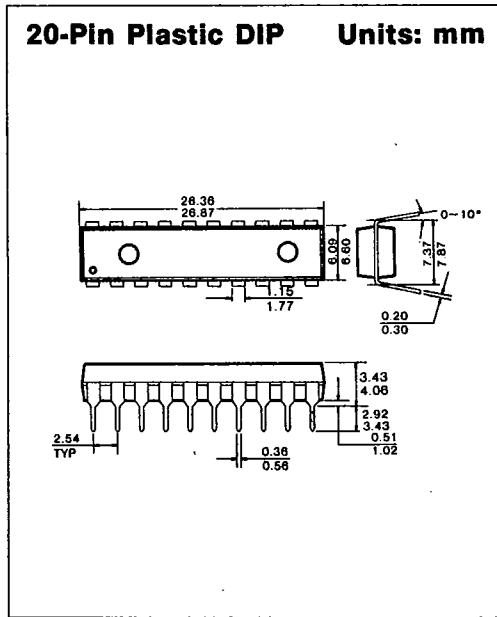
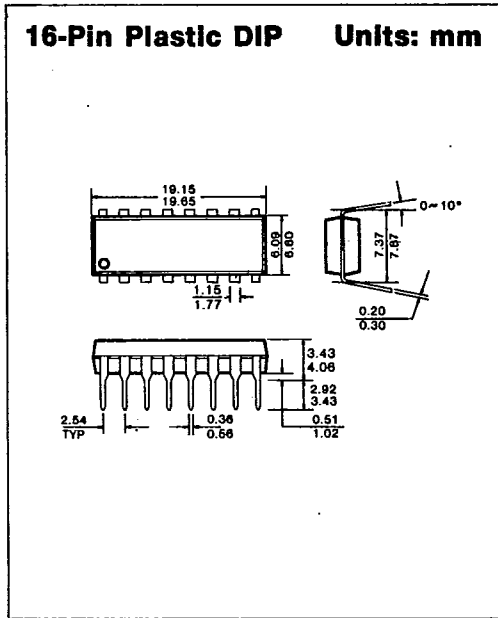
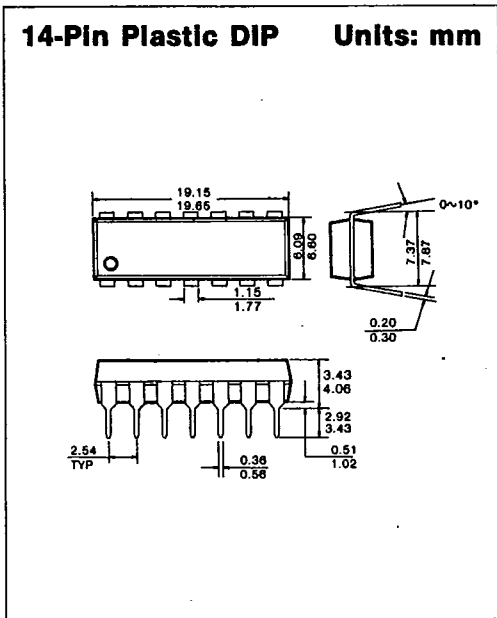
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PACKAGE DIMENSIONS

T-90-20

1. PLASTIC PACKAGES



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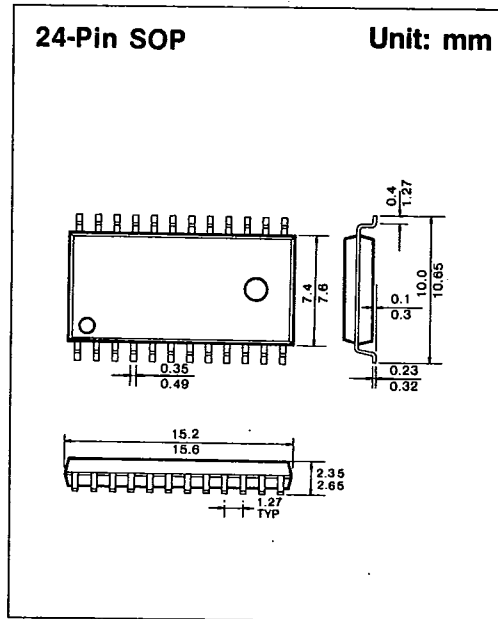
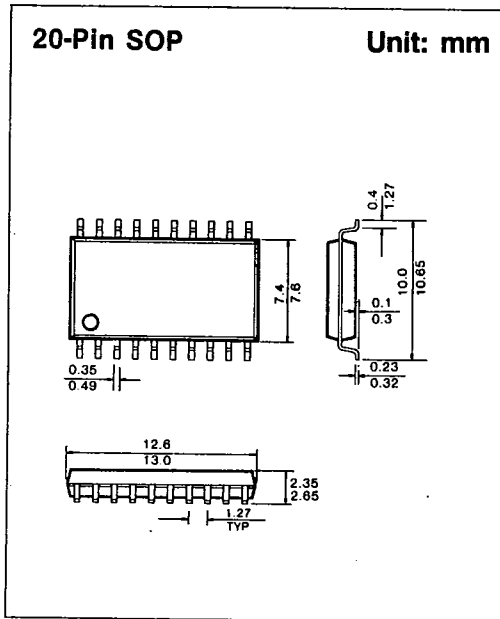
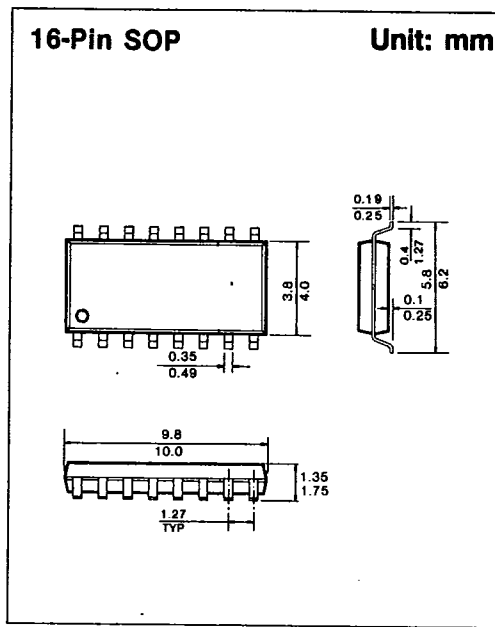
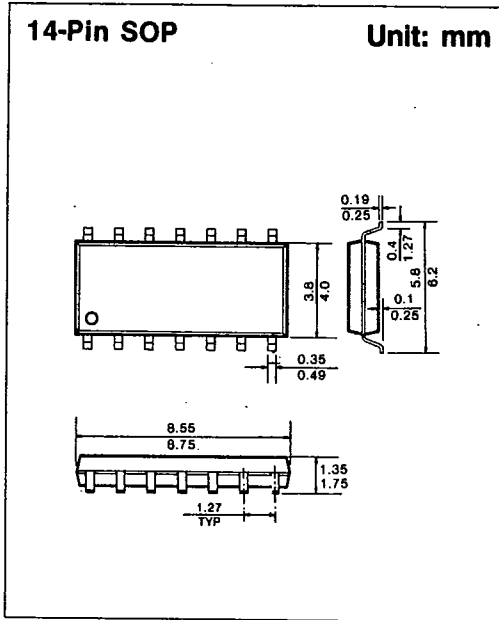
SAMSUNG SEMICONDUCTOR

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PACKAGE DIMENSIONS

T-90-20

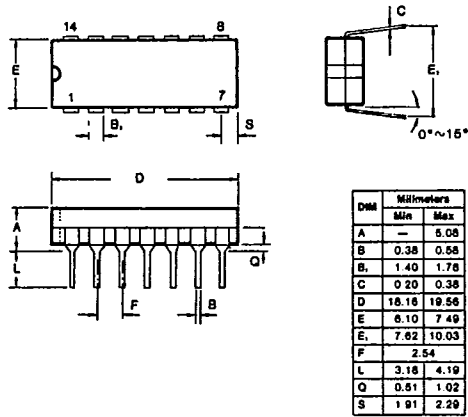


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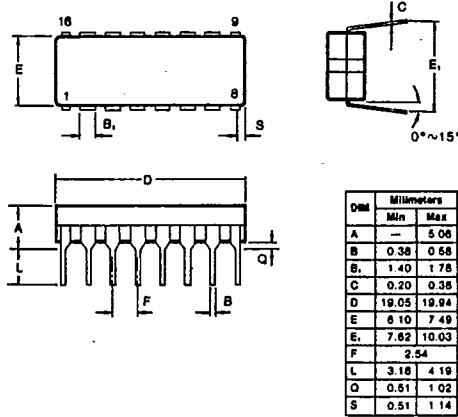
T-90-20

2. CERAMIC PACKAGES

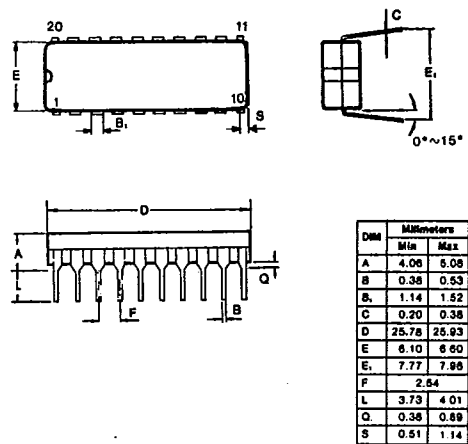
14-Pin Ceramic DIP Units: mm



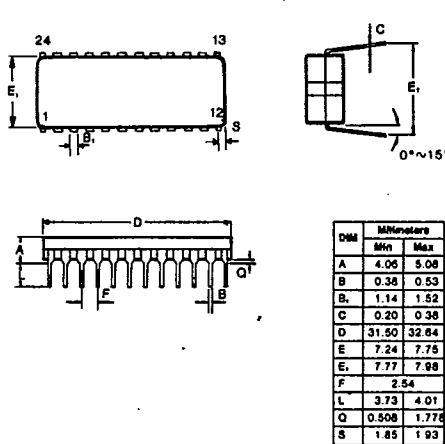
16-Pin Ceramic DIP Units: mm



20-Pin Ceramic DIP Units: mm



24-Pin Ceramic DIP Units: mm



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